

# Reliability Life Data Analysis

*Amnon Ganot - September 2012*



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## Overview

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## Weibull++ 8 Features

- Weibull++ provides the most comprehensive toolset available for reliability life data analysis, calculated results, plots and reporting
- The software supports all data types and all commonly used product lifetime distributions (including the **Weibull model** and the **mixed Weibull model** as well as the **Exponential**, **Lognormal**, **Normal**, **Generalized Gamma**, **Gamma**, **Logistic**, **Loglogistic**, **Gumbel**, **Bayesian-Weibull** and **Competing Failure Modes**).

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## Weibull++ 8 Features (cont.)

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- The software is also packed with tools for related reliability analyses, such as warranty data analysis, degradation data analysis, non-parametric data analysis, recurrent event data analysis and reliability test design.



## In a Nutshell...

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## Life Data Analysis

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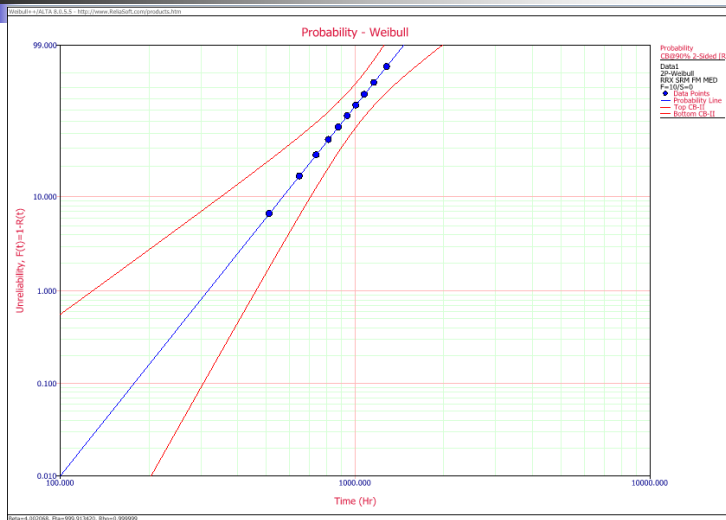
## Life Data Analysis

- In life data analysis, the goal is to model and understand the failure rate behavior of a particular item, process or product
- The models are built by taking the observed “life” data, which can be obtained either from the field or from in-house testing
- Because time is a common measure of product life, the life data points are often called *times-to-failure data*
- There are two general types of *times-to-failure data*:  
complete and censored

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# Probability Plots



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# Quick Calculation Pad

The screenshot shows the "QCP" (Quick Calculation Pad) window. At the top, it displays "Weibull++ Standard Folio: Bulb A - Supplier Data\Data1". The main display area shows:
 

- Upper Bound (0.95): 0.000147
- Failure Rate: 0.000004/Hr
- Lower Bound (0.05): 1.079049E-07

 Below this, there are controls for "Fail. Rate", "Hr", "2S-Both", and "Captions On". The main interface is divided into "Calculate" and "Input" sections.
 

- Calculate:** Includes buttons for Reliability, Prob. of Failure, Cond. Reliability, Cond. Prob. of Failure, Life (Reliable Life, BX% Life, Mean Life), Rate (Failure Rate), and Bounds (Parameter Bounds).
- Input:** Includes "Mission End Time (Hr)" set to 100 and "Confidence Level" set to 0.90.

 At the bottom right, there are "Calculate", "Report", and "Close" buttons.



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## Complete Data

- The simplest case of life data is a data set where the **failure time** of each specimen in the sample is **known**
- This type of data set is referred to as **complete data**, and is obtained by recording the **exact times** when each unit failed



## Censored Data

- **Censored data** means data with **missing information**
- When a unit has failed between observations and the **exact time to failure is unknown**, the time intervals in which the failures occurred are referred to as **interval censored data**
- On the other hand, for non-failed units that **continue to operate after the observation period has ended**, the observed operating times of the units are referred to as **right censored data** or **suspensions**





## Degradation Analysis

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## Degradation Analysis

- **Degradation analysis** is useful for tests performed on highly reliable products that:
  - cannot feasibly be tested to **complete failure** under normal **operating conditions**,
  - are associated with a measurable **performance characteristic** (e.g., the wear in brake pads) and,
  - are not destroyed upon inspection

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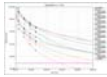
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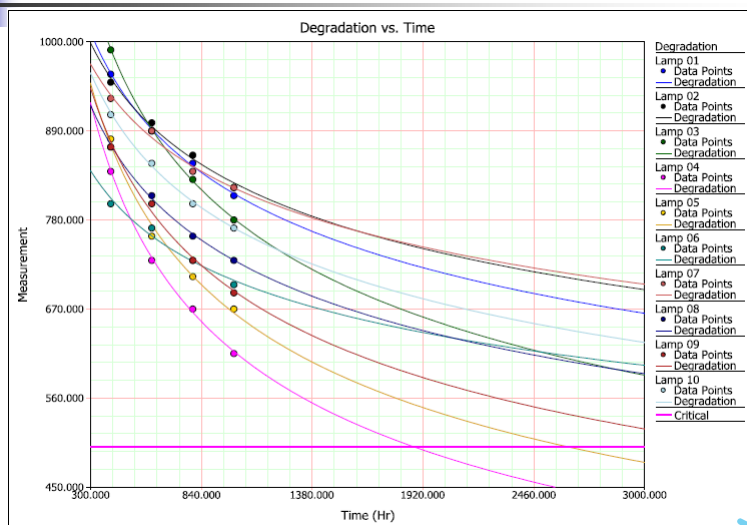
## Degradation Analysis (cont.)



- This analysis consists of two steps:
  - First, the **failure times** of the units on test are **extrapolated** using measurements of their **degradation over time**. (A unit is considered failed when its **degradation reaches a specified critical level**.)
  - Second, once these **failure times** are obtained, **life data analysis** is used to estimate the reliability of the product



## Degradation Vs. Time







## Design of Reliability Tests

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## Design of Reliability Tests

- Weibull++ includes a number of **test design tools** that provide ways to design reliability tests and evaluate/compare proposed test designs
  - Zero-failure demonstration test
  - Detecting differences in reliability
  - Predicting expected failure times


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## Zero-failure demonstration test

- A **zero-failure** test is appropriate when you only want to know, with a given confidence level, whether the **life metric is greater than the specified requirement**
- This sort of test provides a quick and efficient way of accomplishing this
- Note, however, that zero-failure tests generally **cannot be used to determine the actual value of a product's life metric**





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## Detecting differences in reliability

- Sometimes, tests will be performed just for **comparative purposes** (e.g., to show that one product's B10 life is greater than another product's)
- The **Difference Detection Matrix** calculates how much test time is required before it is possible to detect a **statistically significant** difference in a reliability metric (e.g., mean life) of two product designs by analyzing the data from a reliability life test



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## Predicting expected failure times

- In general, this plot tells you that, based on the assumed distribution, you can expect the observed failure times to be within the ranges shown
- If any sequential observed time is outside this range, then the distribution (and thus the reliability) of the observed units should no longer be assumed
- Moreover, if any of the observed failure times is earlier than its predicted interval, then you can infer that the reliability will be less than what was assumed
- Similarly, if any of the actual failure times is greater than its predicted interval, then you can infer that the reliability is greater than what was assumed (at the specified confidence level)

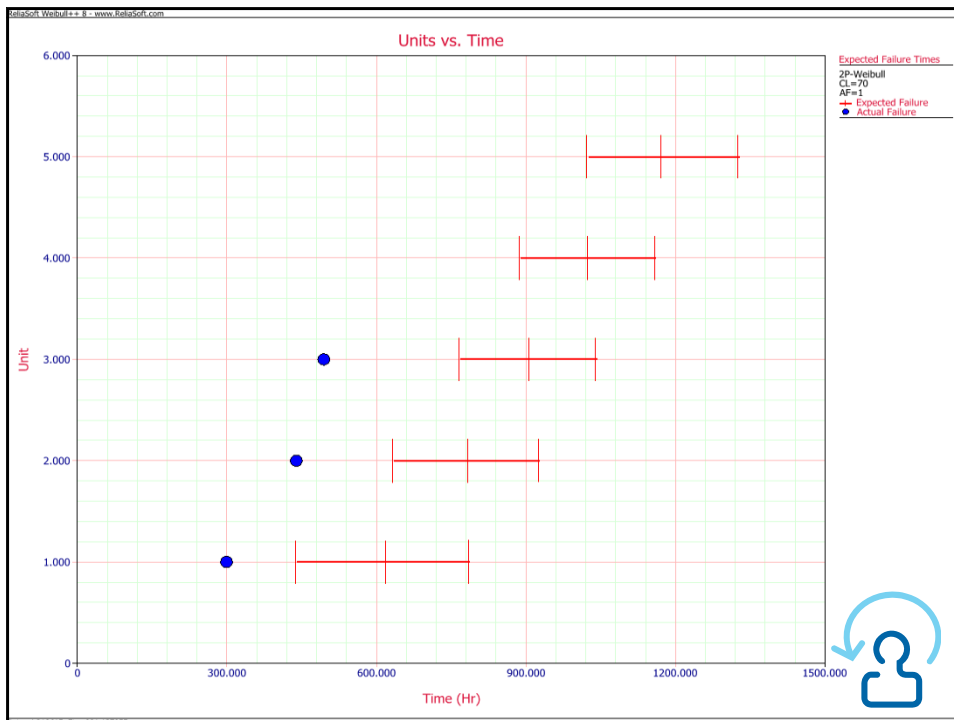


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## Warranty Analysis

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## Warranty Analysis

- **Development testing** allows you to uncover and correct reliability problems **before a product is deployed**; however, there are instances when a problem is not discovered until the product is in the **customer's hands**
- Data obtained from **field failures** can provide valuable information about how a product actually performs in the **real world** as well as **forecasting product returns**

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## Warranty Analysis (cont.)

- Nevada chart format

Returns Period

Month	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18
1		6	13	20	32	38	62	82	97	78	112	113	76	0	0	0	0	0
2			5	9	20	35	52	76	64	76	114	112	89	77	0	0	0	0
3				4	12	19	31	58	56	77	94	87	114	93	76	0	0	0
4					5	13	20	31	39	70	69	104	81	104	108	112	0	0
5						6	10	22	39	48	56	68	89	97	109	92	88	0
6							4	12	22	36	54	61	52	88	101	97	89	94
7								4	10	23	35	53	58	65	68	76	107	78
8									5	10	25	38	33	50	57	79	100	105
9										6	9	22	20	40	41	75	75	80
10											6	12	11	17	29	48	67	67
11												6	4	9	22	40	57	67
12													0	0	1	2	3	8
13														0	0	1	2	5
14															0	0	1	2
15																0	0	1
16																	0	0
17																		0
18																		0



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## Warranty Forecast Analysis (cont.)

B13		19	20	21	22	23	24
1	Bulb B						
2	Bulb B						
3	Bulb B						
4	Bulb B						
5	Bulb B						
6	Bulb B						
7	Bulb B	104					
8	Bulb B	103	97				
9	Bulb B	108	109	102			
10	Bulb B	103	110	110	103		
11	Bulb B	86	98	105	105	99	
12	Bulb B	80	98	112	120	120	112
13	Bulb A	23	57	116	194	247	216
14	Bulb A	7	23	56	116	193	246
15	Bulb A	2	7	23	56	116	193
16	Bulb A	0	2	7	23	56	116
17	Bulb A	0	0	2	7	23	56
18	Bulb A	0	0	0	2	7	23
19	Bulb A	0	0	0	0	2	7
20	Bulb A	0	0	0	0	0	2
21	Bulb A				0	0	0
22	Bulb A					0	0
23	Bulb A						0
24	Bulb A						
Total		616	600	633	726	863	973

**Forecast**

**WARRANTY**

Forecast

Upper Bounds

Lower Bounds

Round Results

Show Subset ID

Use Warranty Length

Length:

**Analysis Summary**

T(0)=...

Failures in selection:



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## Target Reliability Estimation

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## Target Reliability Estimation

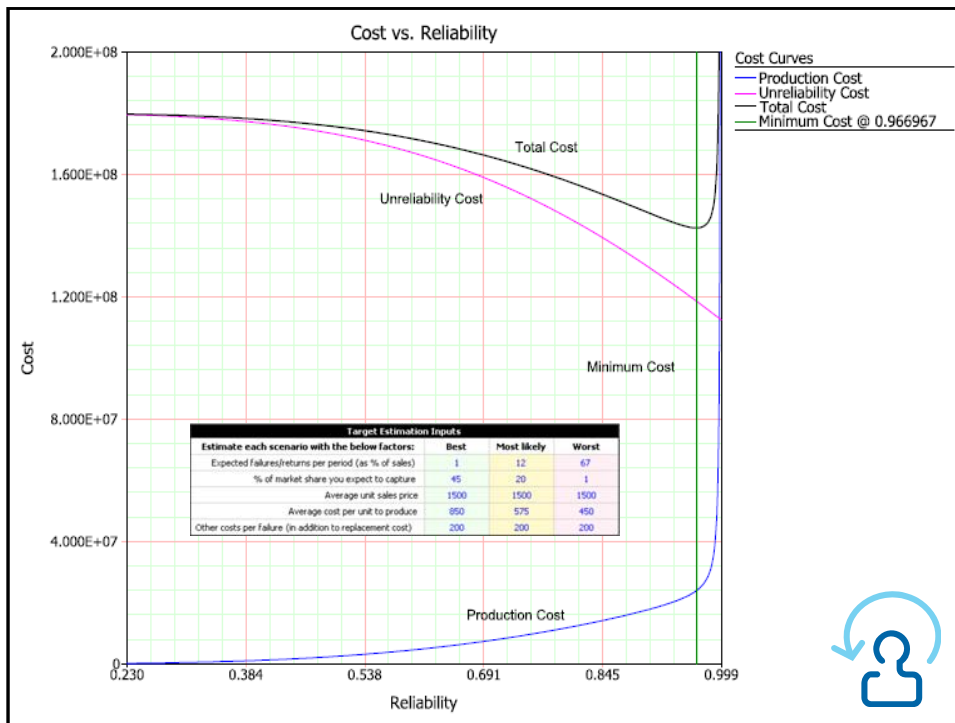
- Deciding on a reliability goal/target involves trade-offs
- This is because higher reliability typically correlates with higher production costs, lower warranty costs and higher market share
- With Weibull++'s Target Reliability tool, you can generate plots that help you visualize and estimate a target reliability that will minimize cost, maximize profit and/or maximize your return on an investment in improving the product's reliability



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## Target Reliability Estimation

Target Estimation Inputs			
Estimate each scenario with the below factors:	Best	Most likely	Worst
Expected failures/returns per period (as % of sales)	1	12	67
% of market share you expect to capture	45	20	1
Average unit sales price	1500	1500	1500
Average cost per unit to produce	850	575	450
Other costs per failure (in addition to replacement cost)	200	200	200

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## Stress-Strength Comparison

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## Stress-Strength Comparison

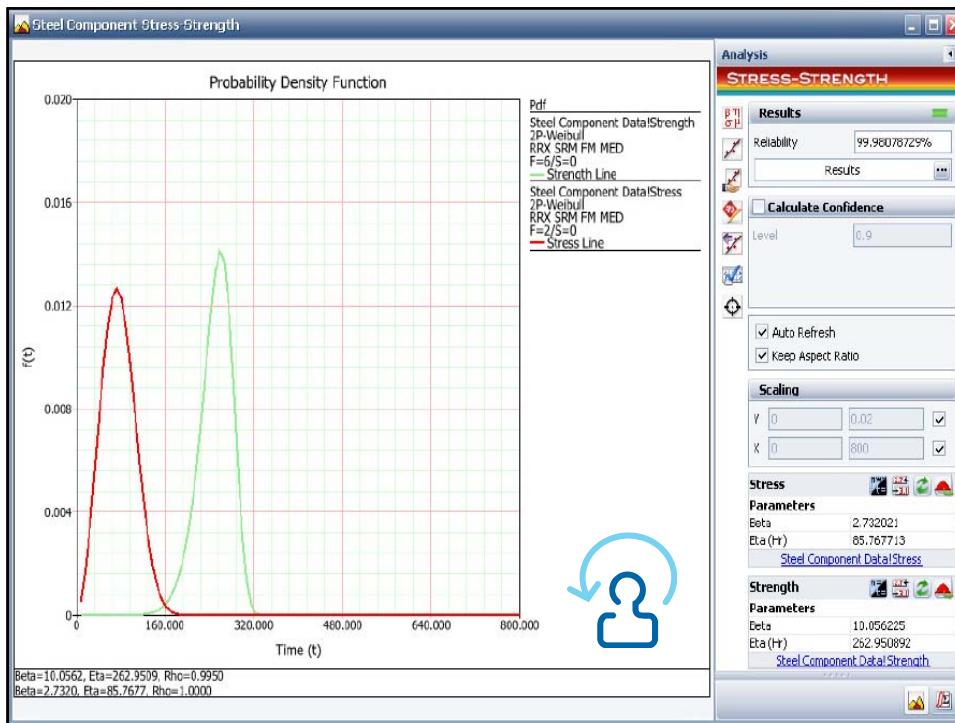
- Generally, the reliability of a product is calculated based on its **ability to perform without failure for a specified period of time**
- In some cases, however, you may need to obtain the reliability of a product based on its **ability to withstand an applied stress without failure**, rather than the length of time it continues to operate
- An example is a wooden beam that may buckle under a load that is over a certain weight limit




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# Competing Failure Modes Analysis



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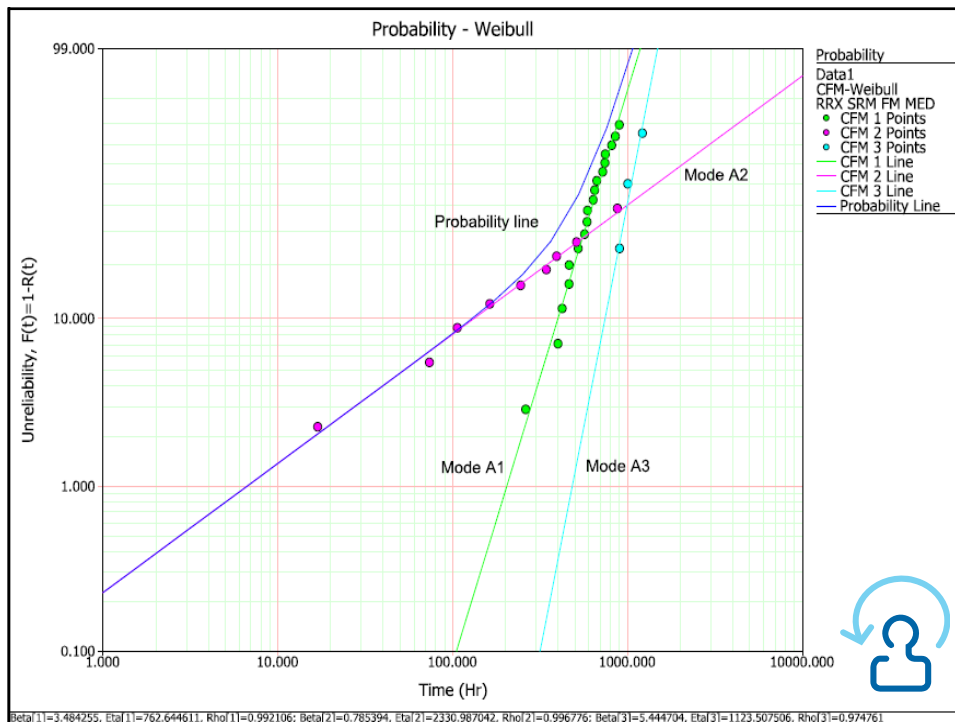
# Competing Failure Modes Analysis

- Competing failure modes analysis is a method of analyzing the reliability of a product that has more than one cause of failure
- The analysis uses the following assumptions:
  - the failure modes are independent, meaning that the occurrence of one mode does not affect the probability of occurrence of the other modes
  - the system will fail if any of the modes occur (i.e., series configuration) and
  - the failure rate behavior for each failure mode is known and can be described with a life distribution and parameters



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## Parametric Recurrent Event Data Analysis



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## Parametric Recurrent Event Data Analysis



- In **life data analysis**, it is assumed that the components being analyzed are **non-repairable**; that is, they are either discarded or **replaced upon failure**
- However, for complex systems such as automobiles, computers, aircraft, etc., it is likely that the **system will be repaired** (not discarded) upon failure
- **Failures are recurring events** in the life of a **repairable system**, and data from such a system are known as **recurrent event data**

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## Parametric Recurrent Event Data Analysis (cont.)

- In the reliability field, **recurrent event data analysis** has many applications such as:
  - Evaluating whether the population **repair (or cost) rate increases or decreases** with age (this is useful for product **retirement** and **burn-in** decisions).
  - Estimating the **average number** or **cost of repairs** per unit on **warranty** or over the **design life** of the product
  - **Comparing two or more sets of data** obtained from **different designs, production periods, maintenance policies, environments, operating conditions**, etc.
  - Predicting future numbers and costs of repairs

## Event Log Data Analysis

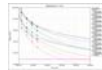


## Event Log Data Analysis

- **Event logs**, or **maintenance logs**, capture information about a piece of equipment's **failures and repairs**, such as the **date/time the equipment failed** and the **date/time the equipment was restored**
- This information is useful for helping companies achieve productivity goals by giving insight about the **failure modes**, **frequency of outages**, **repair duration**, **uptime/downtime** and **availability** of the equipment
- Objective - Obtain the **times-to-failure** and **times-to-repair distributions** of each subsystem



## Summary



- **Life Data Analysis** - In **life data analysis**, the **goal** is to **model and understand the failure rate behavior of a particular item, process or product**
  - Complete Data
  - Censored Data
- **Degradation Analysis** - useful for tests performed on (highly reliable) products that are associated with a measurable **performance characteristic**
- **Warranty Analysis** - Data obtained from **field failures** can provide valuable information about how a product actually performs in the **real world** as well as **forecasting product returns**



## Summary (cont.)



- Target Reliability Estimation - **higher reliability** typically **correlates** with **higher production costs**, **lower warranty costs** and **higher market share**



- Stress-Strength Comparison - reliability of a product based on its **ability to withstand an applied stress without failure**, rather than the length of time it continues to operate



- Competing Failure Modes Analysis - a method of analyzing the reliability of a product that has **more than one cause of failure**



## Summary (cont.)

- Parametric Recurrent Event Data Analysis - **Failures are recurring events** in the life of a **repairable system**, and data from such a system are known as **recurrent event data**
- Event Log Data Analysis - Obtain the **times-to-failure** and **times-to-repair distributions** of each subsystem

QCP

Weibull++ Standard Folio: Bulb A - Supplier Data\Data1

Upper Bound (0.95) 0.000147

**Failure Rate** 0.000004/Hr

Lower Bound (0.05) 1.079049E-07

Fail. Rate Hr 2S-Both Captions On

QUICK CALCULATION PAD Units Bounds Options

**Calculate**

Probability: Reliability, Prob. of Failure, Cond. Reliability, Cond. Prob. of Failure

Life: Reliable Life, BX% Life, Mean Life

Rate: Failure Rate

Bounds: Parameter Bounds

**Input**

Mission End Time (Hr) 100

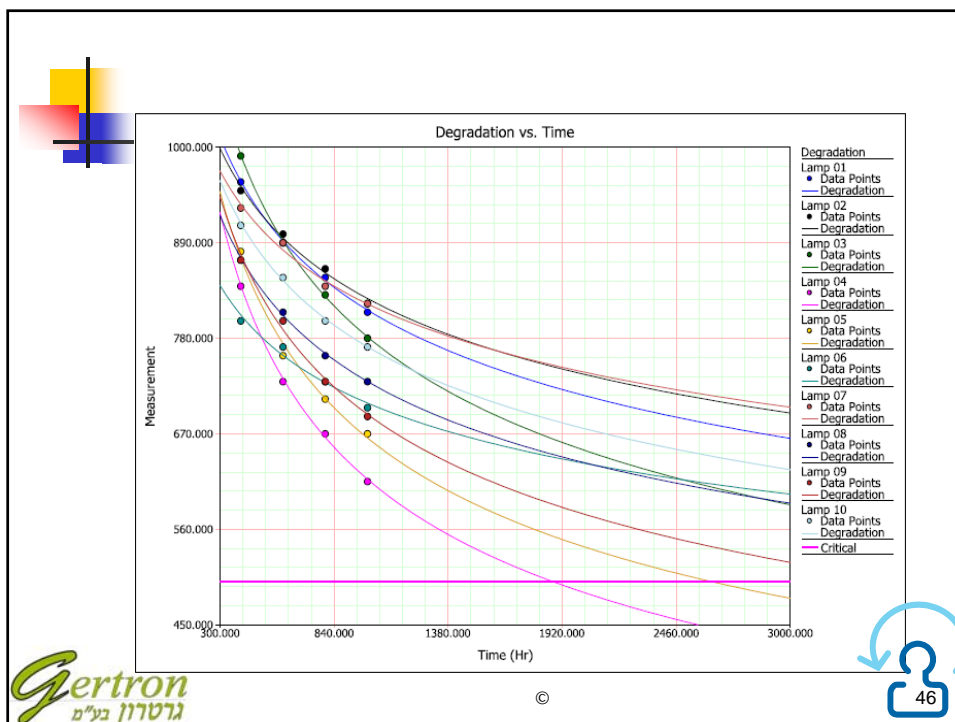
Confidence Level 0.90

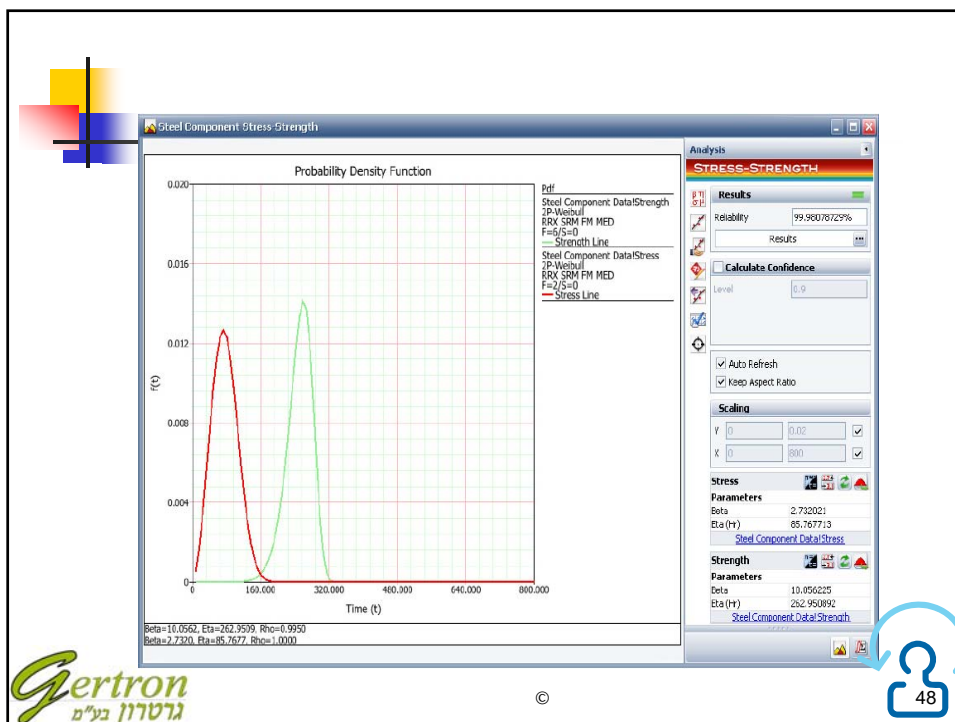
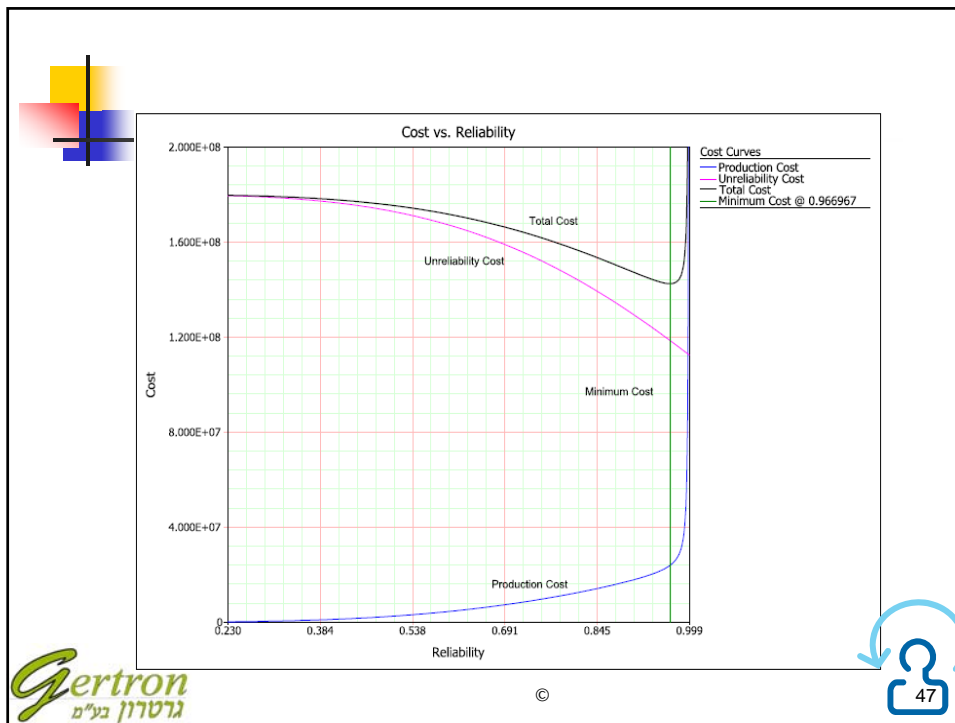
Calculate Report

Close

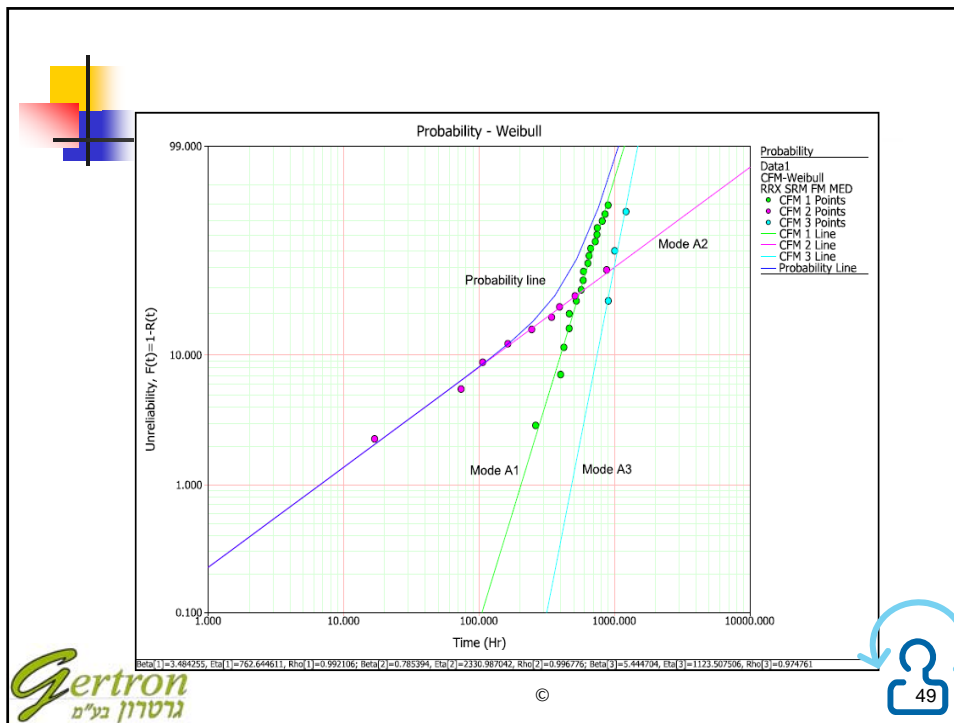
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## Amnon Ganot, CRE

- RAMS Expert at ORBOTECH Ltd. & CTO at GERTRON Ltd. RAMS Consulting Services
- Amnon Ganot is the RAMS expert at Orbotech Ltd. Amnon is working at Orbotech for the last 22 years. Prior to being the RAMS expert, Amnon was the RAMS & Standard Compliance manager of Orbotech.
- During his cadence as the RAMS & Standard Compliance manager, he concentrated on developing methodologies for RAMS such as ALT, FMEA (Quick & Extended), DFM, DFR, Design for Standard Compliance, HALT, etc. Prior to the former job, he was, for more than 25 years, a project manager and system engineer in multidisciplinary projects in the medical, communication and industrial field.
- In the last four years, Amnon is occupied as CTO of Gertron Ltd., performing RAMS consulting services.
- Amnon holds a B.Sc in Electrical Engineering from the Technion Israel Institute of Technology, Israel. Amnon received his MBA from the Tel-Aviv University, Israel. Amnon is an ASQ Certified Reliability Engineer (CRE) as well as ISQ Certified Reliability Engineer (CREI)
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# Questions?



*Thanks for your attention*